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TABLE OF CONTENTS

Assessment of Security Risks and Defenses in Chiplet Systems	1
<i>Hasin Ishraq Reefat, Hossein Pourmehrani, Junie Um, Sylvain Guilley, Naghmeh Karimi</i>	
DART: Dynamic Repair for Interconnect Fault Tolerance in Hybrid Bonding*	12
<i>Partho Bhoumik, Zhichao Chen, Puneet Gupta, Krishnendu Chakrabarty</i>	
Structural Reconstruction of Analog Circuits Using Graph Neural Networks and Transformers	19
<i>Dipali Jain, Guangwei Zhao, Kaveh Shamsi</i>	
SafeTune: Mitigating Data Poisoning in LLM Fine-Tuning for RTL Code Generation	26
<i>Mahshid Rezakhani, Nowfel Mashnoor, Kimia Azar, Hadi Kamali</i>	
Soft Error Reliability Analysis & Hardening of NVDLA MAC Units	31
<i>Nikolaos Chatzivangelis, Nikolaos Betsos, Georgios-Ioannis Paliaroutis, Nikolaos Zazatis</i> <i>Pelopidas Tsoumanis, Frederic Wrobel, Marko Andjelkovic, Christos Sotiriou, Luigi Dilillo</i>	
Cross-Layer Reliability Analysis of Slimmable Neural Networks under Permanent Faults	36
<i>Nikolaos Zazatis, Alessandro Veronesi, Konstantinos Varakliotis, Pelopidas Tsoumanis, Christos Sotiriou</i> <i>Leticia Maria Bolzani Pöhls, Marko Andjelkovic, Davide Bertozzi</i>	
Closing the Loop in LLM-Based Hardware Generation: An Autonomous Agentic Workflow for Robust TPU Design	41
<i>Deepak Vungarala, Kartik Pandit, Gamana Aragonda, Jeremy McLynch, Adeola Adeoye-Davids</i> <i>Bryan Galecio, NhatHai Phan, Abdallah Khreishah, Ramtin Zand, Arnob Ghosh, Shaahin Angizi</i>	
ROCKET: Runtime Operating-Condition Aware KEy Refreshing Technique for Resisting Side-Channel Analysis Attacks	46
<i>Hasin Ishraq Reefat, Hossein Pourmehrani, Jean-Luc Danger, Sylvain Guilley, Naghmeh Karimi</i>	
Exploring Agentic LLM Paradigms for Hardware Verification across Abstraction Levels	53
<i>Sudipta Paria, Swarup Bhunia</i>	
WARP-TPG: Warpage-Aware Test Pattern Generation for Small-Delay Defects*	58
<i>Dhruv Thapar, Arjun Chaudhuri, Krishnendu Chakrabarty</i>	
Reliability Evaluation of Vector-Accelerated Neural Network Inference on a Fault-Tolerant RISC-V SoC for Space Applications	65
<i>Carolina Imianosky, Douglas A. Santos, Wesley Grignani, Luigi Dilillo</i>	
HAT-FI: Hardware-Aware Training for Fault-Tolerant LLM Inference on RRAM-Based Compute-in-Memory	70
<i>Pragya Sharma, Soyed Tuhin Ahmed, Farshad Firouzi, Krishnendu Chakrabarty</i>	
LEAD: Link Exploitability Analysis for Die-to-Die Interconnects in Heterogeneous Integration*	75
<i>Arjun Hati, Eduardo Ortega, Jonti Talukdar, Jim Plusquellic, Krishnendu Chakrabarty</i>	
NERT: Network- and Routing-aware Testing of Interconnects in Fanout Wafer-Level Packaging.	82
<i>Dhruv Thapar, Partho Bhoumik, Arjun Chaudhuri, Krishnendu Chakrabarty</i>	
Automation of Polynomial Formal Verification using Large Language Models	89
<i>Luca Müller, Khushboo Qayyum, Nele Hugo, Muhammad Hassan, Rolf Drechsler</i>	

Late Breaking Results- Proton Beam Experiments of Compiler-based Hardware Fault Tolerance	94
<i>Emilio Corigliano, Davide Baroffio, Federico Reghenzani, Tomas Antonio López, William Fornaciari</i>	
Towards LLM-Based Reasoning for Gate-Level Netlist Tasks	97
<i>Mueen Almasre, Lilas Alrahis</i>	
Algorithm–Technology Co-Optimization for Reliable NVM-CAM Systems	102
<i>Ali Nezhadi, Sina Bakhtavari Mamaghani, Mehdi Tahoori</i>	
Late Breaking Results - New Techniques for Software Test Library Compaction	109
<i>Nikolaos I. Deligiannis, Michelangelo Bartolomucci, Mansour Sohrabian, Riccardo Cantoro</i>	
<i>Matteo Sonza Reorda</i>	
The Fracture Bits in Large Language Models	112
<i>Soyed Tuhin Ahmed, Farshad Firouzi, Krishnendu Chakrabarty</i>	
Pre-processing Functional And Physical Defect Equivalences To Accelerate Cell-Aware Model Generation	117
<i>Reza Khoshzaban, Gianmarco Mongelli, Dorian Ronga, Iacopo Guglielminetti, Michelangelo Grosso</i>	
<i>Eric Faehn, Patrick Girard, Arnaud Virazel, Riccardo Cantoro</i>	
From Language to Logic: Bridging LLMs & Formal Representations for RTL Assertion Generation	124
<i>Nowfel Mashnoor, Hadi Kamali, Kimia Azar</i>	
Defect-based Testing for SRAM Address Decoders	129
<i>Ho-Jie Hsu, Hsien-Chen Lee, Chun-Yu Shen, Po-Tsang Huang, Shih-Chieh Lin, Yung-Jheng Wang</i>	
<i>Ying-Yen Chen, Chien-Yuan Pao, Hung-Yu Lee, Mango Chia-Tso Chao</i>	
Late Breaking Results - Test Selection for In-Field Testing Using a Two-Dimensional Aging Space	136
<i>Irith Pomeranz, Subashini Gopalsamy, Arani Sinha, Yonsang Cho</i>	
Reliable Emerging Electronics in Wearable and Implantable Healthcare Applications	139
<i>Priyanjana Pal, Paula Carolina Lozano Duarte, Suhas Krishna Kashyap, Mehdi B. Tahoori</i>	
<i>Caroline J. Smith, Yuna Jung, Daniel Gulick, Jennifer Blain, Sule Ozev</i>	
Innovative Practices Session: Efficient Multi-Die Test Architecture & Repair Methods	150
<i>Tapan J Chakraborty, Rajesh Pendurkar, Anshuman Chandra, Jennifer Dworak, Moiz Khan</i>	
<i>Vinay Kumar Kotha</i>	
Efficient Trimming Test Approach for STT-MRAMs with Merged Reference Scheme	151
<i>Pei-Yun Lin, Jin-Fu Li</i>	
An Effective Built-In Self-Test Scheme for Digital Computing-In Memories with MAC Function	158
<i>Wen-Ching Liao, Kai-Hsiang Chang, Jin-Fu Li</i>	
Innovative Practices Session: Recent Approaches in Dealing with Silent Data Corruption	165
<i>Harish Dattatraya Dixit, Arani Sinha, Nithya Jagannathan, David P. Lerner, Francesco Angione</i>	
Innovative Practices Session: Applying Analog Scan to Industrial Circuits	166
<i>Stephen Sunter, Marampally Saikiran, Degang Chen, Ashok Mathur</i>	
IABIST: An IJTAG-Compliant Machine Learning-Based Analog BIST Framework for SoC Verification	167
<i>Jules Kouamo, Emmanuel Simeu, Michele Portolan</i>	

Innovative Practices Session: Recent Developments in IEEE Draft Standards P1838a & P3164, and Analog Soft Defects	174
<i>Adam Cron, Sohrab Aftabjahani, Senthil Singaravelu</i>	
TRACK: Telemetry-based Representation Analysis via Centered Kernel Alignment for Silicon Lifecycle Management*	175
<i>Eduardo Ortega, Jonti Talukdar, Hsiao-Ping Ni, Krishnendu Chakrabarty</i>	
Analysis and Mitigation of Cells Programming Misalignments in PCM-based AiMC Cores	182
<i>Alessio Antolini, Lorenzo Greco, Andrea Lico, Francesco Zavalloni, Riccardo Zurla, Emanuela Calvetti</i> <i>Marco Pasotti, Alessandro Cabrini, Eleonora Franchi Scarselli</i>	
Next-Gen Scalable In-System-Test Architecture for Nvidia Automotive Platform	187
<i>Sailendra Chadalavada, Milind Sonawane, Saranyan Sarangan, Alex Hsu, Pavan Javvaji, Shantanu Sarangi</i>	
Innovative Practices Session: Hardware Security and Test	194
<i>Jonti Talukdar, Sohrab Aftabjahani</i>	
Who Checks the Checker? Enhancing Component-level Architectural SEU Fault Tolerance for End-to-End SoC Protection	195
<i>Michael Rogenmoser, Philippe Sauter, Chen Wu, Angelo Garofalo, Luca Benini</i>	
Innovative Practices Session: Recent Developments in IEEE Draft Standards P1687, P1687.2, and P2929	202
<i>Adam Cron, Stephen Sunter, Sankaran Menon, Jeff Rearick, Ilya Wagner, Tapan Chakraborty, Martin Keim</i>	
Accelerating Recurring Failure Search With AI-Based Scandump Anomaly Pattern Detection	203
<i>Lay Wai Kong, Subhiksha Murugesan, Shino Korah</i>	
Security Vulnerabilities of Semiconductor Memories	208
<i>Pravineeth Edara, Biresh K. Joardar, Zakia T. Tisha, Ujjwal Guin, Habib Ur Rahman, Biswajit Ray</i>	
Enhancing Testability & Security of Near-Memory Computing Architectures	219
<i>Hichem Benamara, Sabrina Ait Belkacem, Maria Ramirez-Corrales, Lorenzo Ciampolini</i> <i>Jean-Philippe Noel, Maha Kooli, Lila Ammoura, Ian O'Connor, Patrick Girard, Arnaud Virazel</i>	
Enhancing Robustness of Content-Addressable Memories for In-Memory Search	224
<i>Liu Liu, Tomas Sousa Pereira, Mohammad Mehdi Sharifi, Pengyu Ren, Bo Wen, Can Li, Kai Ni</i> <i>Michael Niemier, X. Sharon Hu</i>	
Innovation Practices: AI Applications to Test and Quality	229
<i>Chen He, Peng Li, Saidapet Ramesh, Fei Su</i>	
SHOUT — Silent Data Corruption Hunting and Observation Using Transformers	230
<i>S. Maryam Ghasemi, Shanmukha Mangadahalli Siddaramu, Tara Gheshlaghi, Sani Nassif</i> <i>Mehdi B. Tahoori</i>	
Toward a User-aware Security Taxonomy for Quantum Computing Platforms	237
<i>Navnil Choudhury, Kanad Basu</i>	
FT-Sparse: Algorithm-Based Fault Tolerance for Sparse CNNs Using Structured Sparsity in GPUs	242
<i>Josie E. Rodriguez Condia, Mohammad Hasan Ahmadilivani, Jaan Raik, Maksim Jenihhin</i> <i>Matteo Sonza Reorda</i>	

A Flexible Framework for Vector Accelerators In-field Testing	249
<i>Gustavo Vilar de Farias, Josie E. Rodriguez Condia, Matteo Sonza Reorda</i>	
LLM4SecurePQC: LLM-Driven and Side-Channel Resilient Hardware Synthesis of PQC Cores	256
<i>Mohammed Nabeel, Buddhi Perera, Zeng Wang, Ozgur Sinanoglu, Johann Knechtel, Ramesh Karri</i>	
ENFOR-SA: End-to-end Cross-layer Transient Fault Injector for Efficient and Accurate DNN Reliability Assessment on Systolic Arrays	261
<i>Rafael B. Tonetto, Marcello Traiola, Fernando Fernandes Dos Santos, Angeliki Kritikakou</i>	
Learning Quantum Algorithm Footprints to Circumvent Obfuscation: An End-to-End Approach	268
<i>Donald Lushi, Samah Mohamed Saeed</i>	
DefectVICL: Data-Efficient Wafer Defect Classification with Vision In Context Learning	273
<i>Md Fahim Ul Islam, Soyed Tuhin Ahmed, John Carulli, Krishnendu Chakrabarty</i>	
Non-Intrusive THz Chiplet Calibration Using Deep Neural Networks	280
<i>Amirata Tabatabavakili, Mohammed Ayman Habib, Osei Brempong, Morteza Fayazi, Ehsan Afshari</i>	
Scan Chain Reordering for Improving Test Coverage with Compression	285
<i>Hairui Cai, Zezhong Wang, Yu Huang, Naixing Wang, Zhouxing Su, Zhipeng Lv</i>	
Compact Functional Test Pattern Generation for DNNs Using Evolution Strategies	292
<i>Tara Gheshlaghi, Dina A. Moussa, Michael Hefenbrock, Mehdi B. Tahoori</i>	
Forensics of Quantum Processors using Program Queue Depth Analysis	299
<i>Rupshali Roy, Swaroop Ghosh</i>	
Digital Calibration and Correction Techniques for Digital Phase-Locked Loops	304
<i>Mingyang You, Qiaochu Zhang</i>	
FVRuleLearner: Operator-Level Reasoning Tree (Op-Tree)-Based Rules Learning for Formal Verification	309
<i>Lily Jiaxin Wan, Chia-Tung Ho, Yunsheng Bai, Cunxi Yu, Deming Chen, Haoxing Ren</i>	
Trust Calibration for RF and Analog Mixed-Signal Systems: A Survey of Lightweight Hardware Security	317
<i>Bustana Teene, Ankit Mittal</i>	
A gm-C Oscillator-Based On-Chip Offset Calibration Technique for Analog Amplifiers	322
<i>Jhanavi Kodethoor, Can Etiz, Alex Currie, Tejasvi Das</i>	
C2C: Cell-to-Cell Controllability Evaluation for Partial Scan Selection	327
<i>Hairui Cai, Zihao Wang, Liuzheng Wang, Fei Yang, Mingqi Li, Lingxiang Liao, Yu Huang, Zhouxing Su, Zhipeng Lv</i>	
Machine learning calibration for radios	334
<i>Shamma Nasrin, Arindam Sanyal</i>	
Analog Correlators with Applications to Low-power Radar and Spectrum Sensing	339
<i>Aswin Undavalli, Kareem Rashed, Shantanu Chakrabarty, Arun Natarajan, Aravind Nagulu</i>	
RTL-Forge: CNF-Anchored, LLM-Assisted Verilog Generation	344
<i>Prithwish Basu Roy, Akashdeep Saha, Manaar Alam, Johann Knechtel, Michail Maniatakos, Ozgur Sinanoglu, Ramesh Karri</i>	

MoD-CiM: A Mixture-of-Defenses Framework Against Power-Hammering Attacks in Multi-Tenant Compute-in-Memory	351
<i>Ashish Reddy Bommana, Soyed Tuhin Ahmed, Farshad Firouzi, Krishnendu Chakrabarty</i>	
Late Breaking Results – Feature-Aware Trojan Alteration to Evade ML-Based Detection	356
<i>Lizi Zhang, Navid Nader Tehrani, Azadeh Davoodi, Rasit Onur Topaloglu</i>	
WALET: SHAP-Guided Classification of Wafer-Level E-Test Variability for Early Manufacturing Risk Detection	359
<i>Ching-Yi Chang, Matthew Nigh, John Carulli, Yiorgos Makris</i>	
WaferIntel: A Lightweight, SME-Driven Framework for Advanced Defect Pattern Analysis	366
<i>Dmitri V. Kalashnikov, Jianqiao Huang, Pan Yan</i>	
Late Breaking Results - High-Throughput Metastability Characterization of Arbiters using HDC-based BIST	373
<i>Abdullah Sahruri, Martin Margala</i>	
Experimental Validation of Spatial Autocorrelation Framework for RowHammer Test Optimization	376
<i>Vineet Suresh Kumar, Mohammad Farmani</i>	
AI-Assisted Hardware Security Verification: A Survey and AI Accelerator Case Study	383
<i>Khan Thamid Hasan, Md Ajoad Hasan, Nashmin Alam, Md. Touhidul Islam, Upoma Das Farimah Farahmandi</i>	
Can Agents Secure Hardware? Evaluating Agentic LLM-Driven Obfuscation for IP Protection	390
<i>Sujan Ghimire, Parsa Mirfasihi, Muhtasim Alam Chowdhury, Veeramani Pugazhenthir Harish Kumar Dharavath, Farshad Firouzi, Rozhin Yasaei, Pratik Satam, Soheil Salehi</i>	
Temporal Reference Scouting Logic for PVT Reliable Logic Computation-in-Memory	395
<i>Shanmukha Mangadahalli Siddaramu, Ali Nezhadi, Mahta Mayahinia, Sule Ozev, Mehdi B. Tahoori</i>	
Late Breaking Results - Diagnostic Test Templates for Two-Cycle Gate-Exhaustive Faults	402
<i>Irith Pomeranz</i>	
VTS2026 Contest Publication: TTTC’s E.J. McCluskey Best Doctoral Thesis Award	405
<i>Luca Benini, Paolo Bernardi, Alberto Bosio, Swarup Bhunia, Riccardo Cantoro, Degang Chen Krishnendu Chakrabarty, Jayeeta Chaudhuri, Bastien Deveautour, Gabriele Filippini, Angelo Garofalo Salvatore Pappalardo, Sudipta Paria, Michael Rogenmoser, Philippe Sauter, Michael Sekyere, Chen Wu</i>	
A Physics-Informed Machine Learning Framework for Electromigration Time-to-Failure Prediction	423
<i>Saeid Karimpour, Emmanuel Nti Darko, Kelvin Tamakloe, Degang Chen</i>	
Late Breaking Results – Confidence-Gap–Driven Functional Test Pattern Generation for Enhancing Functional Safety of CNN Accelerators	430
<i>Tong-Yu Hsieh, Ching-Hsin Hsu, Wei-Ji Chao</i>	
Variation-Aware Post-Manufacturing Calibration for ReRAM-based Content-Addressable Memory	433
<i>Mahta Mayahinia, Haneen G. Hezayyin, Mehdi Tahoori</i>	
Secure eFPGA-Enabled Edge LLM Inference: Architectural and Hardware Countermeasures	440
<i>Voktho Das, M Zafir Sadik Khan, Jafar Vafaei, Kimia Azar, Hadi Kamali</i>	
Hardware Acceleration for Zero-Knowledge Proof: Recent Advances and Challenges	445
<i>Pengzhou He, Debapriya Basu Roy, Jiafeng Xie</i>	

Accelerating Analog Test through Firmware-Hardware Driven Parallelism	455
<i>Krishna Pramod Madabhushi, Ayush Jain, Logan Pukett, William Jahner, Eslam Hag</i>	
Late Breaking Results - A Systematic Vulnerability Analysis of MRAM-Based Compute-in-Memory against Side-Channel Attacks	462
<i>Hossein Pourmehrani, Yashas Krishnamohan, Sumukh Bhanushali, Saurabh Dhiman, Rajendra Bishnoi Arindam Sanyal, Farshad Firouzi, Naghmeh Karimi</i>	
Late Breaking Results – Compressed Bit-Level Timing-Error Predictors via Binary Neural Networks	465
<i>Georgios Chatzitsompanis, Nikolaos Kostakis, Georgios Karakonstantis</i>	
2.5D/3D Chiplet-based Integration: New Dimensions in Design and Testing	468
<i>Ganap A. Tewary, Partho Bhounik, Pragnya S. Nalla, Yu Cao, Krishnendu Chakrabarty, Jeff Zhang</i>	
High-Purity, Low-Cost DAC-Based Multitone Waveform Generation for Built-In-Self-Test Applications	480
<i>Emmanuel Nti Darko, Saeid Karimpour, Degang Chen</i>	
Coverage-Aware Scan-Chain Reordering Under Iso-Power Constraints for Programmable Low-Power LBIST	487
<i>Yumei Hu, Hairui Cai, Xiangheng Xie, Zhipeng Lv, Zhouxing Su, Yaning Wang, Yu Huang, Zezhong Wang Xing Wang</i>	
Special Session: Reliability Assessment of DNN Models and Inference on Systolic Arrays	494
<i>Natalia Cherezova, Salvatore Pappalardo, Annachiara Ruospo, Bastien Deveautour, Lorenzo Fezza Artur Jutman, Ernesto Sanchez, Alberto Bosio, Matteo Sonza Reorda, Maksim Jenihhin</i>	
Late Breaking Results - Close-to-Functional Tests for Two-Cycle Interconnect Faults	504
<i>Irith Pomeranz</i>	
VTS2026 Student Forum:	507
<i>Davide Baroffio, Federico Reghenzani, William Fornaciari, Dipal Halder, Sandip Ray</i>	